

**Search Notes**

Application/Control No.

10/655,580

Examiner

D. I. Lee

Applicant(s)/Patent under  
Reexamination

HAKUSHI ET AL.

Art Unit

2876

**SEARCHED**

Class	Subclass	Date	Examiner
235	492 436 441	5/6/2005	D.L.
711	103		
	150-152		
365	222 *		
	226 *		
	233		
	189.01		
	230.01 *		
	230.03 *		
	230.05		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST text search attached. PLUS search	5/6/2005	D.L.